Search Notes



Application/Control No
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10/005,778 Examiner

Erin M. File

Applicant(s)/Patent	unde
Reexamination	

LI ET AL.

**Art Unit** 

2634

SEARCHED				
Class	Subclass	Date	Examiner	
375	343	12/17/2004	EMF	
714	795	12/17/2004	EMF	
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
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SEARCH NOT (INCLUDING SEARCH		)
	DATE	EXMR
EAST US PAT, USPGPUB, EPO, JPO DERWENT, IBM	12/17/2004	EMF
PALM INVENTORSHIP	12/17/2004	EMF
IEEE Explore Keyword Search	12/20/2004	EMF
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